Appl. No. 10/748,734 Amdt. Dated October 17, 2007 Reply to Office Action of July 18, 2007

Attorney Docket No. 88519.0001 Customer No.: 26021

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1-3. (Canceled)
- 4. (Currently Amended) An electrode structure comprising:
- a transparent electrode including ZnO; and
- an Mg-doped ZnO film formed on <u>disposed on a light emission side of an outer</u> <u>surface of</u> the electrode <u>that is opposite to a substrate of a semiconductor device.</u>

wherein the electrode is a component of disposed on a the semiconductor device.

- 5. (Currently Amended) An electrode structure comprising:
- a transparent electrode including ZnO; and
- an Mg-doped ZnO film formed on <u>disposed on a light emission side of an outer</u> <u>surface of</u> the electrode <u>that is opposite to a substrate of a semiconductor device</u>,

wherein the electrode is a component of disposed on a $\underline{\text{the}}$ semiconductor device, and

the semiconductor device includes GaN

- (Previously Presented) The electrode structure of Claim 4, wherein the Mg-doped ZnO film overlies an upper surface of the electrode.
 - (Canceled)
- (Previously Presented) The electrode structure of Claim 4, wherein a first metal pattern is formed on the Mg-doped ZnO film.

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- (Previously Presented) The electrode structure of Claim 4, wherein the electrode is disposed on a semiconductor layer of the semiconductor device, and a second metal pattern is formed on the semiconductor layer.
- (Previously Presented) The electrode structure of Claim 4, wherein the Mg-doped ZnO film improves acid resistance of the transparent electrode.
- (Previously Presented) The electrode structure of Claim 4, wherein the
 electrode is disposed on a semiconductor layer of the semiconductor device, and the
 semiconductor layer is formed on a substrate.
 - 12. (Canceled).
- 13. (Currently Amended) A light emitting device comprising: a semiconductor layer formed on a substrate of a semiconductor device; a ZnO transparent electrode formed on the semiconductor layer; and an Mg-doped ZnO film formed on disposed on a light emission side of an outer surface of the ZnO transparent electrode that is opposite to the substrate.

wherein the semiconductor layer comprises a GaN system semiconductor layer.

- 14. (Currently Amended) A light emitting device comprising: a semiconductor layer formed on a substrate of a semiconductor device;
- a ZnO transparent electrode formed on the semiconductor layer; and
- an Mg-doped ZnO film formed on <u>disposed on a light emission side of an outer</u> <u>surface of</u> the ZnO transparent electrode that is opposite to the substrate.

wherein the semiconductor layer comprises an n-type GaN system semiconductor layer formed on the substrate, an emission layer formed on the

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n-type GaN system semiconductor layer, and a p-type GaN system semiconductor layer formed on the emission layer.

- (Previously presented) The light emitting device of Claim 13, wherein the Mg-doped ZnO film overlies an upper surface of the ZnO transparent electrode formed on the semiconductor layer.
 - 16. (Canceled).
- (Previously presented) The light emitting device of Claim 13, wherein a first metal pattern is formed on the Mg-doped ZnO film.
- (Previously presented) The light emitting device of Claim 13, wherein a second metal pattern is formed on the semiconductor layer.
- (Previously presented) The light emitting device of Claim 13, wherein the Mg-doped ZnO film improves acid resistance of the light emitting device.
 - 20-25. (Canceled).
- 26. (New) The electrode structure of Claim 4, wherein the semiconductor layer is formed on the substrate that is different from the semiconductor layer.